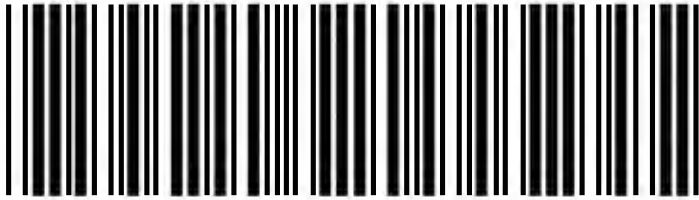


<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10575171</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>KIM, YOUNG-LAK</p>
	<p>Examiner</p> <p>Munjal Patel</p>	<p>Art Unit</p> <p>2617</p>

SEARCHED			
Class	Subclass	Date	Examiner
370	310	3-26-2008	NR
370	328	3-26-2008	NR
370	338	3-26-2008	NR
370	422.1	3-26-2008	NR
455	403	3-26-2008	NR
455	422.1	3-26.2008	NR
455	436	3-26-2008	NR
455	437	3-26-2008	NR
455	439	3-26-2008	NR
370	338	6/9/2008	mp
455	422	6/6/2008	mp
375	220-222	6/9/2008	mp
370	335,441,479	6/9/2008	mp
455	439, 403, 422.1, 436, 437, 422	12/4/2008	mp
370	338, 335, 441, 479, 422.1, 328, 310	12/4/2008	mp
455	439, 403, 422.1, 436, 437, 422	2/14/2010	mp
370	338, 335, 441, 479, 422.1, 328, 310	2/14/2010	mp

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST History	4-9-2008	NR
EAST Search	6/5/2008	mp
IEEE database	6/5/2008	mp
PLUS Search	6/5/2008	mp
PALM Search	6/6/2008	mp
EAST Search	12/2/2008	mp
PALM Search	12/2/2008	mp
Updated EAST Search	6/10/2009	mp
Google Patent Search	6/10/2009	mp
Updated EAST Search	2/14/2010	mp
Updated Google Patent Search	2/14/2010	mp

INTERFERENCE SEARCH

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Class	Subclass	Date	Examiner

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